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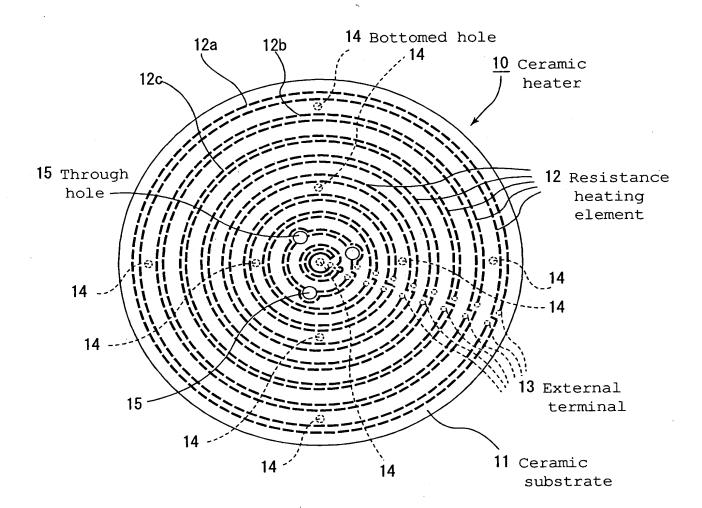
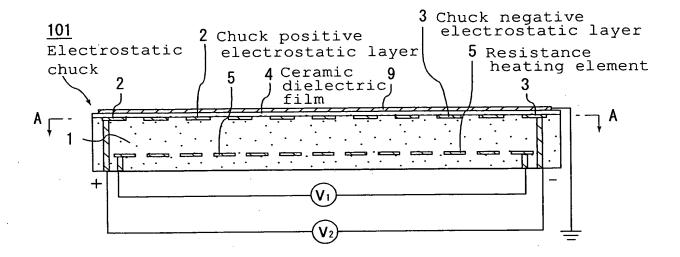


FIG. 2 10 9 Silicon wafer 11a 26 Supporting pin 12 Wafer treating face 11. - 12 ~19 Conductor filled through hole 15 Bottom face - 13

FIG. 3



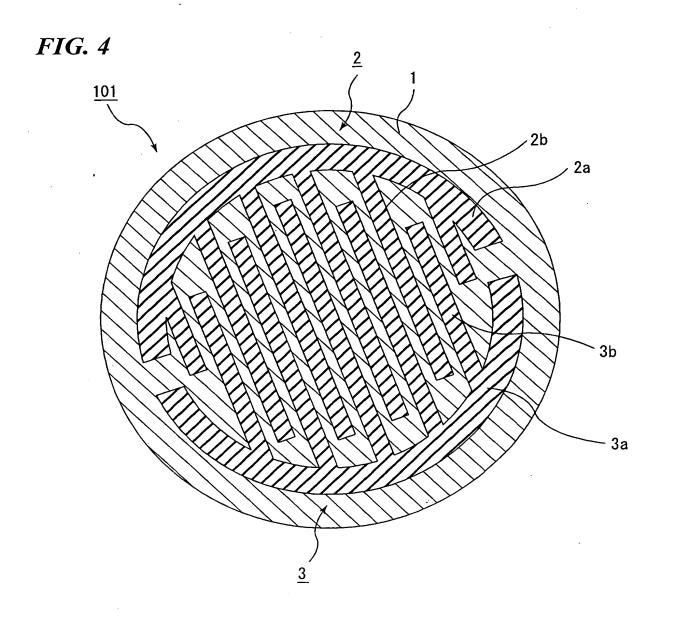


FIG. 5

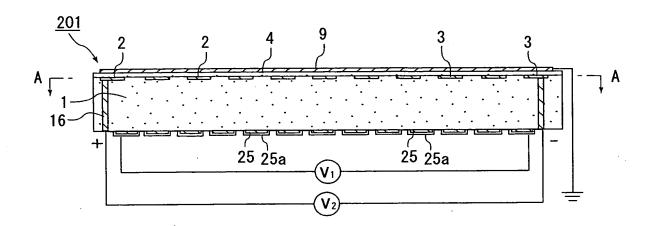


FIG. 6

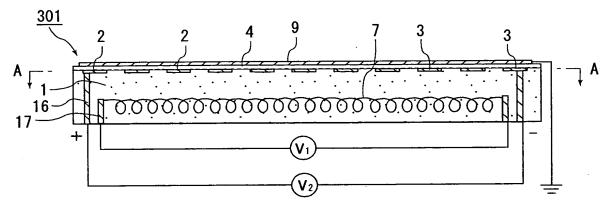
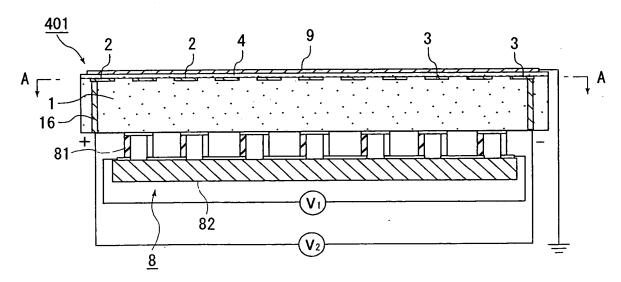
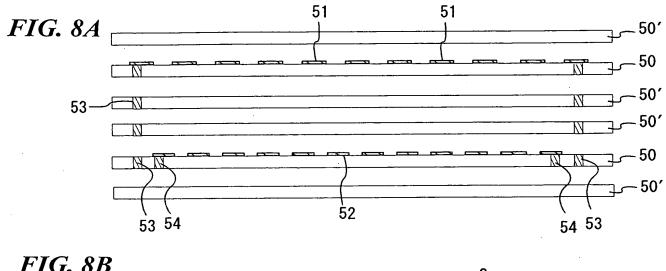
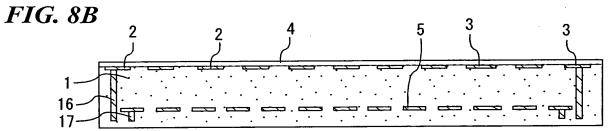
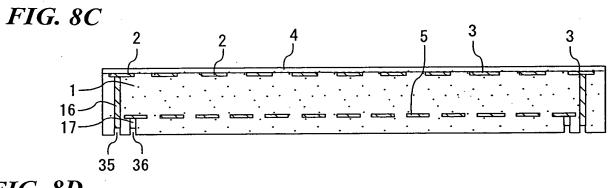


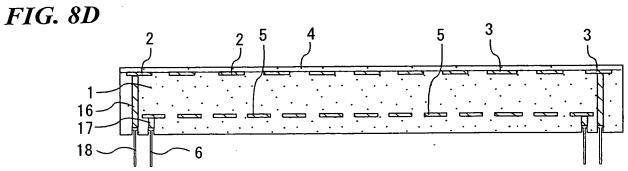
FIG. 7

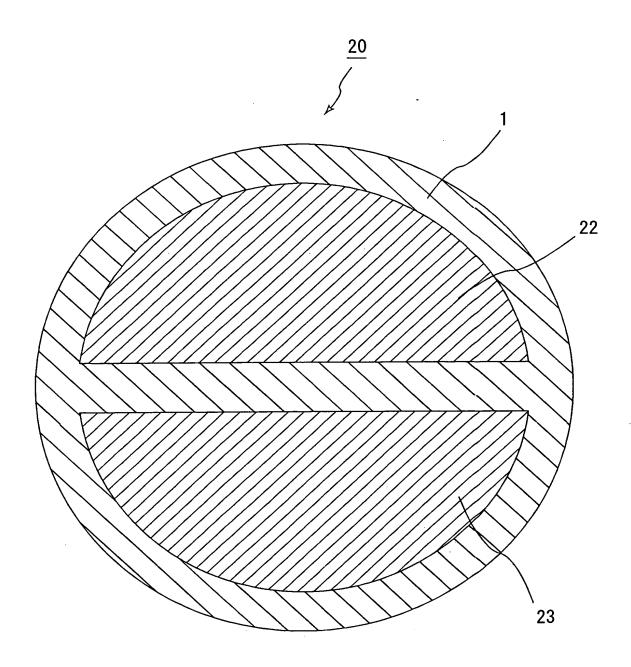


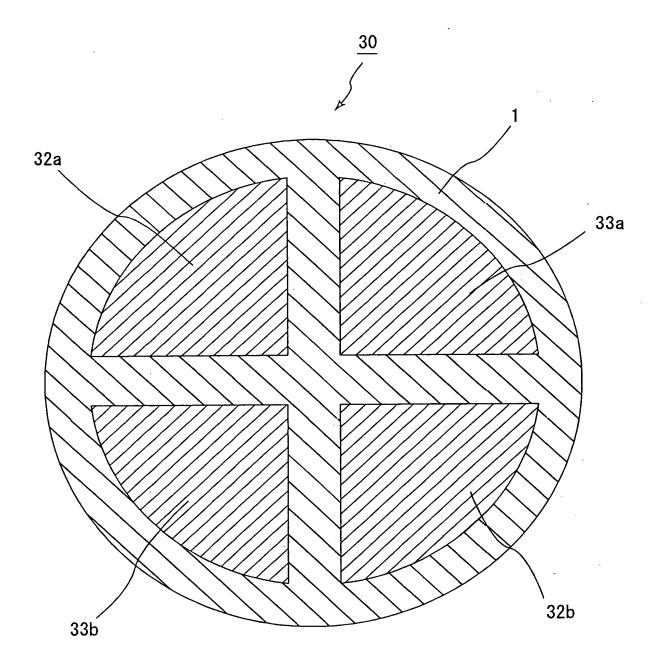












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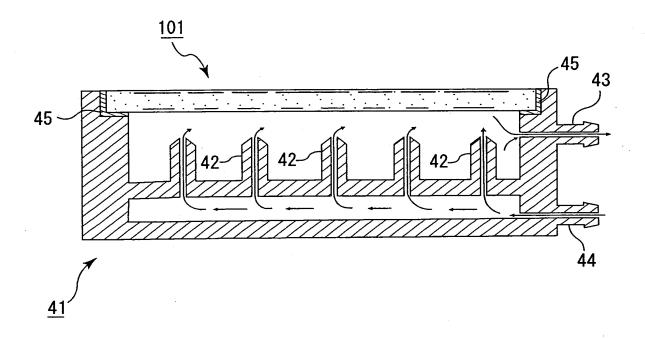


FIG. 12

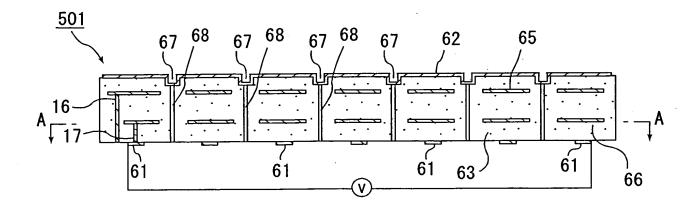


FIG. 13

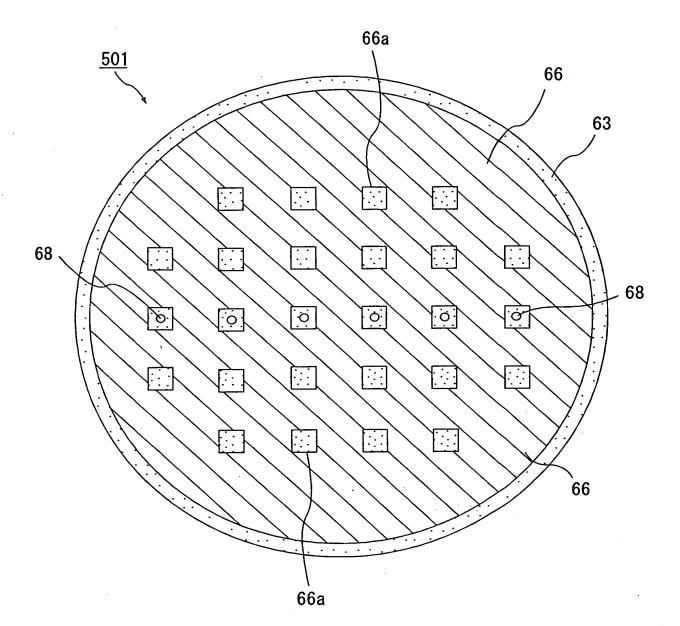


FIG. 14

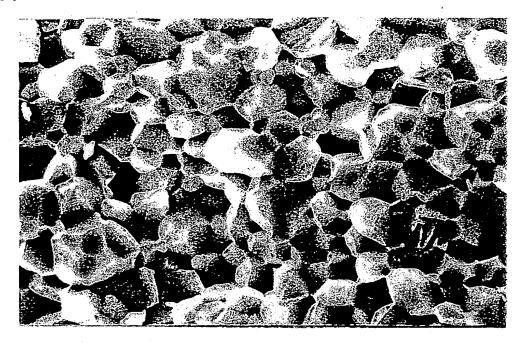


FIG. 15

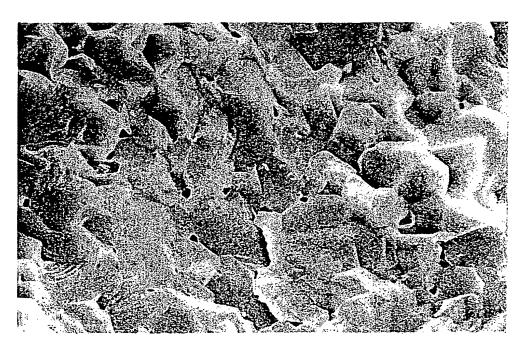


FIG. 16

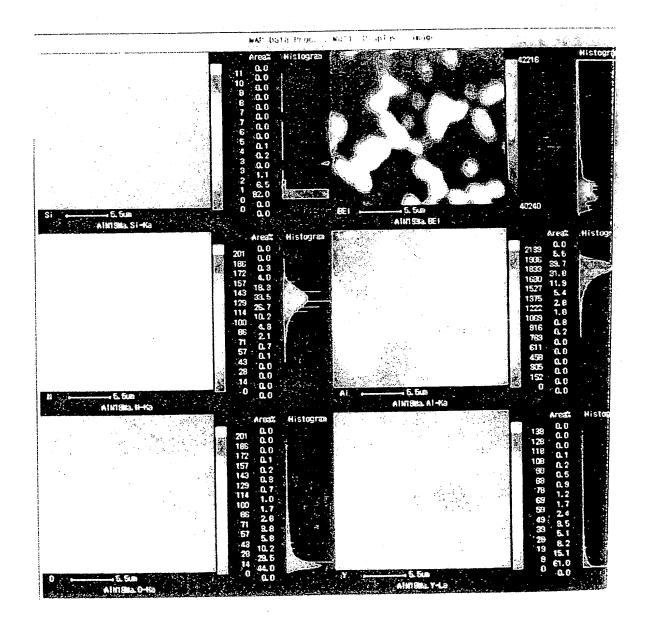


FIG. 17

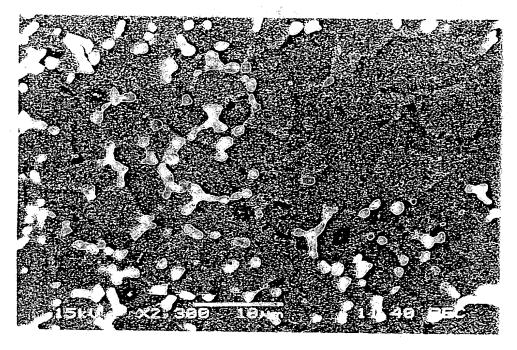


FIG. 18

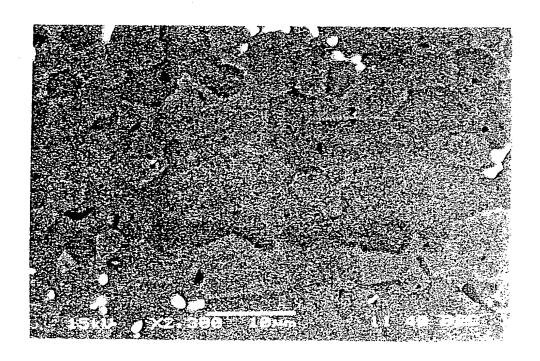


FIG. 19

